

Application/Control No.	Applicant(s)/Patent under Reexamination
10/585,634	FUJII ET AL.
Examiner	Art Unit
Zelalem Eshete	3748

	SEAR	CHED	
Class	Subclass	Date	Examiner
123	90.16	12/28/07	P
	92.35	1418107	
		-	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u>.l</u>	·			

(INCLUDING SEA	ARCH :	ES STRATEGY	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR				
•							
		_					
		•					
 		· ,					
	į						